

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DKT. NO.
500.41080X00

SERIAL NO.

US PTO
00047007
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MORIYA, et al.

FILING DATE

January 14, 2002

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
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FOREIGN PATENT DOCUMENTS

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						Yes	No
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AT				
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

52	AU	TAKAGI, et al., "A New I-V Model for Stress-Induced Leakage Current Including Inelastic Tunneling", IEEE Transactions on Electron Devices, Vol. 46, No. 2, February 1999, pp. 348-354
52	AV	CAMPBELL, et al., "Titanium dioxide (TiO ₂)-based gate insulators", IBM J. Res. Develop. Vol. 43, No. 3, May 1999, pp. 383-392
	AW	
	AX	
	AY	
	AZ	

Examiner	Date Considered
	9/27/02